

Preliminary Technical Program of Test Forum 2014

Tuesday, November 25th, 2014

Time	Titles	Speakers or additional info
8:30-9:00	Registration	
9:00-9:15	Welcome/Introduction	Knut Båtstøløkken
9:15-10:15	Key Note Session	<i>Chairman: Knut Båtstøløkken</i>
9:15-10:15	Historical perspective and future visions of test development in Ericsson	Sören Mellgren, Ericsson
10:15-10:45	Exhibitor Forum: short presentations	<i>Chairman: Mick Austin</i>
10:45-11:15	Coffee Break / Exhibition	
11:15-12:45	Session 1: JTAG based test	<i>Chairman: Lars Kongsted-Jensen</i>
11:15-11:45	Combining Boundary Scan and Functional Test using a JTAG controlled Tester on Chip (ToC)	Jan Heiber, Göpel ESA
11:45-12:15	JTAG and Analog circuits	Mick Austin, JTAG Technologies
12:15-12:45	IJTAG Case Study: Chip Fault Diagnostics in a Board Environment	Kent Zetterberg, Asset Intertech
12:45-14:00	Lunch	
14:00-15:30	Session 2: Test Strategies and Test Quality	<i>Chairman: Birger Schneider</i>
14:00-14:30	Measurement System Analysis - Can You Trust Your Measurement System?	Mattias Ericsson, AddQ Consulting
14:30-15:00	Test & Quality Strategy	Morten Pedersen, CIM Industrial Systems
15:00-15:30	Accurate Calibration of Time and Frequency	Staffan Johansson, Testhouse Nordic AB
15:30-16:00	Coffee Break / Exhibition	
16:00-17:30	Session 3: Functional Test 1	<i>Chairman: Bjørn B. Larsen</i>
16:00-16:30	Test Platform Standardization: Increase product quality with reduced cost of test	Johan Hillergren, NI
16:30-17:00	Problems related to version changes in LabVIEW and TestStand	Tapani Talvitie, Teleste
17:00-17:30	Fruit & Refreshments / Exhibition	
17:30-19:00	Panel debate: "Why do test people fail to prevent faults like No Fault Found?"	<i>Panel moderator: Birger Schneider</i>
19:30	Dinner	

Wednesday, November 26th, 2014

Time	Titles	Speakers or additional info
9:30-10:30	Session 4: Invited speaker	<i>Chairman: Magnus Rönnqvist</i>
09:30-10:30	Applying Learnings from Emerging Component Test to Board and System Test	Bill Eklow, Cisco Systems
10:30-11:00	Coffee Break / Exhibition	
11:00-12:30	Session 5: Functional test 2	<i>Chairman: Mauri Aalto</i>
11:00-11:30	Platform Based Test System Development - increased quality and lower development cost	Karin Hellqvist, DVel Juha Ojaniemi, Espotel
11:30-12:00	Modular NI TestStand applications	Claus Sørensen, DSE
12:00-12:30	Overcoming the challenges of making a reliable fiber optic connections in ATE applications	Gary Clayton, MAC-Panel
12:30-13:30	Lunch	
13:30-15:00	Session 6: Automatic inspection and structural test	<i>Chairman: Erik Larsson</i>
13:30-14:00	Welcome to the 3rd-Dimension! 3D-SPI, 3D-AOI, 3D-AXI, everything from a single source. Outstanding 3D technologies ensure maximum test coverage	Andreas Türk, Göpel, AOI/AXI
14:00-14:30	How to integrate the Flying Probe as a flexible test solution	Lothar Diez, SPEA
14:30-14:50	Closing Session: Test Forum concluding remarks and Introduction to the BASTION Workshop	<i>Knut Båtstøløkken, Kitron Artur Jutman, Testonica Lab</i>

BASTION Project Fringe Workshop (free of charge for NTF participants)

14:50-15:10	Coffee Break	
15:10-16:10	Board test coverage challenges for high-performance electronics	<i>Chairman: Thomas Wenzel, GOEPEL electronic</i>
15:10-15:30	Defect classes, testability metrics, DPMO	Christophe Lotz, Aster Technologies
15:30-15:50	No Failure Found problem and embedded instrumentation solutions	Artur Jutman, Testonica Lab
15:50-16:10	Combining functional test and embedded instruments	Matteo Sonza-Reorda, Politecnico di Torino
16:10-17:10	IEEE 1687 IJTAG and hierarchical test	<i>Chairman: Gunnar Carlsson, Ericsson</i>
16:10-16:30	Challenges in hierarchical test and monitoring	Carsten Laudert, Infineon Technologies
16:30-16:50	IEEE 1687 IJTAG standard: design and optimization strategies	Erik Larsson, University of Lund
16:50-17:10	Verification of IEEE 1687 IJTAG infrastructure	Rene Krenz-Baath, HSHL
17:10-17:40	Coffee break	
17:40-18:40	Ageing failure resilience in the field and lab	<i>Chairman: Gerard Rauwerda, Recore Systems</i>
17:40-18:00	Ageing mechanisms: effect detection and test instrumentation	Hans Kerkhoff, University of Twente
18:00-18:20	Can we have a fast and accurate NBTI-aging assessment at the gate-level?	Jaan Raik, TU Tallinn
18:20-18:40	IEEE 1687 Instrumentation networks for ageing failure management	Artur Jutman, Testonica Lab
18:40-19:30	Wine and Cheese Panel: discussing presented topics in-depth with the audience	<i>Chairman: Bill Eklow, Cisco Systems Panel: all the 8 workshop speakers</i>